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				Application Number	10/596,736-Conf. #9973
				Filing Date	June 22, 2006
				First Named Inventor	Frank Fiedler
				Art Unit	N/A
				Examiner Name	Not Yet Assigned /Sunray R. Chang/ (09/15/2008)
Sheet	1	of	1	Attorney Docket Number	20793/0204864-US0

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
	AA*	US-5,703,714	12-30-1997	Kojima et al.	
	AB*	US-6,133,561	10-17-2000	Toshimitsu et al.	
	AC*	US-5,499,097	03-12-1996	Ortyn et al.	
	AD*	US-5,260,825	11-09-1993	Nagano et al.	
	AE*	US-2004/0190129-A1	09-30-2004	Peter et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>3</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)				
	BA	WO-96/18924	06-20-1996	Olympus Optical Co. et al.		√
	BB	EP-1 445 635	08-11-2004	Leica Microsystems et al.		√
	BC	DE-19839777	03-11-1999	Nippon Kogaku Kk		√

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NON PATENT LITERATURE DOCUMENTS			
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Examiner Signature	/Sunray R. Chang/ (09/15/2008)	Date Considered	
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